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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/710,522	07/18/2004	Chung-Chih Chen	NAUP0598USA	4521
27765 7590 12/04/2007 NORTH AMERICA INTELLECTUAL PROPERTY CORPORATION			EXAMINER	
P.O. BOX 506	P.O. BOX 506 TADAYYON ESLAMI, TABA MERRIFIELD, VA 22116			AMI, TABASSOM
MERRIFIELD	, VA 22116		ART UNIT PAPER NUMBER	
·			1792	
			NOTIFICATION DATE	DELIVERY MODE
			12/04/2007	ELECTRONIC

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

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		Application No.	Applicant(s)	
•		10/710,522	CHEN, CHUNG-CHIH	
Office Action Summary		Examiner	Art Unit	
		Tabassom T. Tadayyon-Eslami	1792	
Period fo	The MAILING DATE of this communication app	<u> </u>	correspondence address	,
A SH WHIC - Exter after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DA nsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. Deperiod for reply is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tin vill apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	N. nely filed the mailing date of this communication. ED (35 U.S.C. § 133).	·
Status				
• —	• ——	action is non-final. nce except for formal matters, pro		
Dispositi	ion of Claims		•	
5)□ 6)⊠ 7)□	Claim(s) 1-11 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) 1-11 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or	wn from consideration.		
Applicati	ion Papers			
10)	The specification is objected to by the Examine The drawing(s) filed on is/are: a) access Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine	epted or b) objected to by the drawing(s) be held in abeyance. Se ion is required if the drawing(s) is ob	e 37 CFR 1.85(a). pjected to. See 37 CFR 1.121(d).	
Priority (under 35 U.S.C. § 119			
12) a)	Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau See the attached detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receiv u (PCT Rule 17.2(a)).	tion No red in this National Stage	
2) Notice 3) Information	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO/SB/08) er No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:	Date	

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DETAILED ACTION

Drawings

The drawing is received on 10/08/2007. This drawing is appropriate.

Claim Interpretation

Claim 7 include sixth paragraph of 35 U.S.C. 112. The term "means for preventing" has been interpreted in light of the disclosure at [0023] as a sheet of foil. The term "light inhibiting means for transferring the wafer" has been interpreted as the foil sheet.

Claim Rejections - 35 USC § 112

- 1. The following is a quotation of the first paragraph of 35 U.S.C. 112:
 - The specification shall contain a written description of the invention, and of the manner and process of making and using it, in such full, clear, concise, and exact terms as to enable any person skilled in the art to which it pertains, or with which it is most nearly connected, to make and use the same and shall set forth the best mode contemplated by the inventor of carrying out his invention.
- 2. Claim 7-11 are rejected under 35 U.S.C. 112, first paragraph, as failing to comply with the written description requirement. The claim contains subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed had possession of the claimed invention. The light inhibiting area that transfers the substrate (in addition to the foil as means to prevent the light) is not in disclosure.
- 3. The following is a quotation of the second paragraph of 35 U.S.C. 112:
 - The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

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4. Claims 7-11 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention. Based on MPEP 2181.III and 2185, the term "first light inhibiting means for transferring" is unclear, because it invokes sixth paragraph of 35 U.S.C. 112, but the specification does not describe corresponding structure to perform the function. For the purpose of applying art, the light inhibiting means for transferring the wafer has been interpret as at least inclusive of the same sheet of foil.

Claim Rejections - 35 USC § 102

5. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 6. Claims 7, 9 and 11 are rejected under 35 U.S.C. 102(b) as being anticipated by Bryan C. Chung (U. S. Patent: 6361614), here after Chung.

Chung teaches.

A wafer cleaning system comprising a wet cleaning tool for performing a wafer cleaning tool for performing a wafer cleaning process [column 2, line 37] and a light inhibiting means for preventing a wafer to be cleaned from light exposure during said wafer cleaning process [column 3, line 3] (from entering the wafer to the chamber it gives at least partial shadowing which is light blocking).

Claim 9 is rejected. Chung teaches the said wet processing tool is a single – wafer-cleaning tool [claim 5].

Claim 11 is rejected. Chung teaches the said wafer is a semiconductor wafer [column 3, line 11].

Claim Rejections - 35 USC § 103

- 7. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 8. Claims 1-6, 8 and 10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Bryan C. Chung (U. S. Patent: 6361614), here after Chung further in review of A.
- Beverina et. al. "Copper Photocorrosion phenomenon during Post CMP Cleaning", Electrochemical and Solid-State Letters, Vol. 3(2000)156, here after Beverina.

Chung teaches,

a method of wafer cleaning [column 2, line 33], comprising:

Providing a wet cleaning tool [fig. 1 and column 3, line 30].

Transferring the wafer into said wet cleaning tool in a light inhibited manner [column 3, line 30] (such as from the entering to the chamber gives at least partial shadowing; that is light blocking); and

Cleaning said main surface of said wafer by contacting a cleaning solution in said light inhibited manner [column 2, line 37].

Chung does not specifically teach the wafer comprises exposed copper feature and a dielectric film. Beverina teaches,

A wet cleaning process [abstract, line 1], comprising;

Preparing a wafer having a main surface comprising at least one exposed copper feature and a dielectric film [page 156, line 5] and eliminating the light eliminates the corrosion [abstract, line 4].

Therefore it would have been obvious to one of ordinary skill in the art at the time of invention was made to have a method of wet cleaning that Chung teaches on the wafer structure that Beveria teaches, because Beveria teaches eliminated the light during the cleaning step eliminates the corrosion. Therefore, it is suitable to use Chung's method to eliminate the light during the processing.

Claim 2 is rejected since Chung teaches the wafer is a semiconductor [column 3, line 11].

Claim 3 is rejected. Chung and Beveria teach the limitation of claim 1. Beveria further teaches the exposed copper feature is damascened into said dielectric film [page 156, column 1, and line 6]. Therefore it would have been obvious to one of ordinary skill in the art at the time of invention was made to have a method of wet cleaning that Chung teaches on the wafer structure that Beveria teaches, because Beveria teaches eliminated the light during the cleaning step eliminates the corrosion on copper feature into the said dielectric layer.

Claim 4 is rejected. Chung and Beveria teach the limitation of claim 1 and Chung further teaches the wafer is not exposed to the light during the step of cleaning process [column 3, line 13].

Claim 5 is rejected. Chung teaches the tool comprises a succession of sinks containing cleaning solution [column 1, line 41].

Claim 6 is rejected. Chung teaches the said wet processing tool is a single – wafer-cleaning tool [claim 5].

Claim 8 is rejected. Chung teaches the limitation of claim 7 and he further teaches the tool comprises a succession of sinks containing cleaning solution [column 1, line 41].

Claim 10 is rejected. Chung teaches the limitation of claim 7. Chung does not teach the exposed copper feature is damascened into said dielectric film. Beveria further teaches the exposed copper feature is damascened into said dielectric film [page 156, column 1, line 6]. Therefore it would have been obvious to one of ordinary skill in the art at the time of invention was made to have a method of wet cleaning that Chung teaches on the wafer structure that Beveria teaches, because Beveria teaches eliminated the light during the cleaning step eliminates the corrosion on copper feature into the said dielectric layer.

Response to Argument

Applicant's arguments filed on Oct. 08, 2007 have been fully considered but they are not persuasive. Applicant argues on the route and during the process of transporting

the wafer to the wet cleaning tool the light is blocked from the wafer, because of the moisture in the air will induce copper corrosion. However the applicant does not claim that moisture in the air will induce copper corrosion. U. S. Patent: 6361614, here after Chung, teaches that the light is prevented from entering to the processing chamber by welding, screwing or nailing the light blocking material to the chamber [column 4 lines 6-10] and so it will remain during the transferring wafer to the chamber. The foil of Chung inherently at least partially blocks the incoming light.

Conclusion

Applicant amendment necessitated the new ground (s) of rejection presented in this office action Accordingly, **THIS ACTION IS MADE FINAL.** Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tabassom T Tadayyon-Eslami whose telephone number is 571-270-1885. The examiner can normally be reached on 7:30-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Cleveland can be reached on 571-272-1418. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

T.T

SUPERVISORY PATENT EXAMINER